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FAKULTÄT FÜR ANGEWANDTE WISSENSCHAFTEN

Gastvortrag

Zeit: Freitag, 12. 3. 1999, 15.00 Uhr s.t.
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Test Generation and Test Compaction for Sequential Circuits

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Abstract

Test generation for sequential circuits has proved to be difficult. Over the past 40 years several tachniques have been studied. In this talk we will present a new approach that has yielded promising results both in fault coverage and test generation time. We also present a method to compact test sequences which forms the basis of the test generation method proposed.

Gastgeber: Prof. Dr. Bernd Becker

Alle Interessenten sind recht herzlich eingeladen.

Organisation : Prof. Dr. B. Becker / F. Schmiedle

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